

No.2663A

32-Bit PPC LED Erasing Head Driver

Features

· High-speed, high-voltage silicon gate CMOS device

• Contains high-speed shiftable (5MHz max) 32-bit shift register, 32-bit latch, output driver on/off control circuit, 32-bit N-channel open drain output driver.

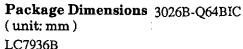
• Serial shift data is shifted on the positive transition of the clock signal (CLOCK).

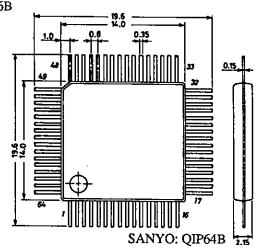
• 32-bit latch data is changed on the negative transition of the LATCH pad signal and is held on the positive transition.

• The STROBE pad signal, BEO pad signal can be used to exercise on/off control of the output driver.

- All output drivers can be turned on by setting 32-bit latch regardless of shift register data. (TEST=Hi, STROBE=Lo, BEO=Hi)
- Complete separation of logic circuit GND (1 pad) and thermal driver GND (4 pads)
- Maximum ratings of driver output: V_O=15V, I_{OL}=30mA
- Logic unit operating voltage: V_{DD} =4.5V to 5.5V

Absolute Maximum Ratings at Ta-	=25°C			unit
Maximum Supply Voltage	V_{DD}		-0.3 to +7.0	V
Input Voltage	V_{I}		-0.3 to $V_{DD}+0.3$	V
Output Voltage	$V_{O}(1)$	S _{OUT} output	-0.3 to $V_{DD}+0.3$	V
	V ₀ (2)	D1 to D32 output Output Tr off	15	V
Output Circuit	I_{O}	D1 to D32 output, per output	30	mA
Allowable Power Dissipation	Pd max	QIP-64 package at 70°C	450	mW
Operating Temperature	Topr	QIP-64 package	0 to +70	°C
Storage Temperature	Tstg	QIP-64 package	-35 to +125	°C



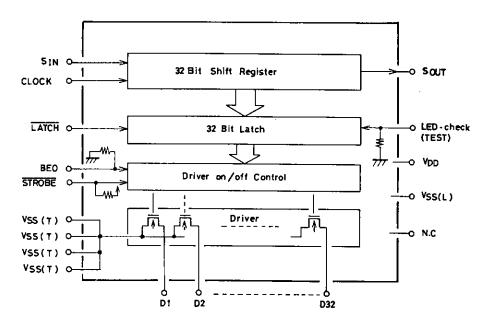


Allowable Operating Conditions at Ta=0 to +70°C									
			Pin N	Tame		min	typ	max	unit
Supply Voltage	V_{DD}	V_{DD}				4.5		5.5	v
"H"-Level Input Voltage	V_{IH}		LOCK, LATO STROBE, LE		(TEST)	$0.8V_{\mathrm{DD}}$		V_{DD}	V
"L"-Level Input Voltage	V_{IL}		LOCK, LATO STROBE, LE		(TEST)	$V_{SS}(L)$		$0.2V_{DD}$	Ÿ
Clock Frequency	f_{CLK}	CLOC	K Duty: 50	%				5.0	MHz
Clock Pulse Width	$t_{\mathrm{W}_{\mathbf{g}}}$	CLOC	CK C			75			ns
Clock Rise/Fall Time	t_r , t_f	CLOC	:K					200	ns
Data Setup Time	t_{DS}	S _{IN} , C	LOCK			100			ns
Data Hold Time	t_{DH}	S_{IN} , C	LOCK			50			ns
Latch Pulse Width	t_{WL}	LATC	Ħ			100			ns
Electrical Characteristic	s at T	a=25°C							
"H"-Level Input Current		I _{IH} (1)	Pin N S _{IN} , CLOCK			min	typ	max 10	unit µA
HITTI I amal I ama Communi		T (0)	LATCH						
"H"-Level Input Current		$I_{IH}(2)$	BEO, LED-	•	EST)	12		72	μA
"L"-Level Input Current	-	I _{IL} (1)	S _{IN} , CLOCE LATCH	ζ.		-10			μA
"L"-Level Input Current		$I_{IL}(2)$	STROBE			-72		-12	μΑ
"H"-Level Output Voltage		V _{OH}	S _{OUT}	V _{DD} = I _{OH} =-	=5V, -0.5mA	V_{DD} -0.5			V
"L"-Level Output Voltage		V _{OL} (1)	S _{OUT}	V _{DD} =	=5 V,),5mA			0.5	V
"L"-Level Output Voltage		V _{OL} (2)	D1 to D32	V _{DD} = I _{OL} =3	=5V, 30 mA			0.5	V
Output Off-State Leakage		I_{OFF}	D1 to D32	$V_0=1$	15 V			20	μΑ
Current									
Input Capacitance		C_{IN}		CLO			5.0		pF
Operating Current Dissipa	tion	I_{DD}	V_{DD}		=5MHz,	lood		5	mA
all outputs: no load Switching Characteristics at Ta=25°C									
on morning of land to the time	o at 1	u-20 0	Pin N	ame			min	typ m	ax unit
Clock Latch Delay Width		t _{CL}	CLOCK,		V _{DD} =5V	,	100	-7 _F	ns
Latch Clock Delay Width		t _{LC}	CLOCK,		$V_{DD}=5V$		0		ns
"H"-Level Output		t _{PLH} (1)			V _{DD} =5V		·	40	00 ns
Propagation Delay Time		FLA (-)	D1 to D32	2	Dn: R _L =			· · ·	
		t _{PLH} (2)	BEO, STE	ROBE	V _{DD} =5V Dn: R _L = CL=			30	00 ns
		t _{PLH} (3)	CLOCK,	S _{OUT}	V _{DD} =5V S _{OUT} : C _r			20	00 ns
"L"-Level Output Propagation Delay Time		t _{PHL} (1)	D1 to D32	2	$V_{DD}=5V$ $Dn: R_{L}=$ $C_{L}=$			20	00 ns
		t _{PHL} (2)	BEO, STF D1 to D32		$V_{DD}=5V$ $Dn: R_{L}=$ $C_{L}=1$	1.0 k Ω		10	00 ns
		t _{PHL} (3)	CLOCK,	Sour	V _{DD} =5V S _{OUT} : C _I	, _=15pF		20	00 ns

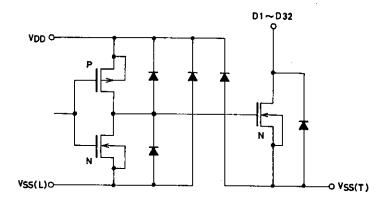
LED Driver On/Off Truth Table

Latch Data (Q)	BEO	STROBE	LED Driver
0	0	0	OFF
1	0	0	OFF
0	1	0	OFF
1	1_	0	ON LED on
0	0	1	OFF
1	0	1	OFF
0	1	1	OFF
1	1	1	OFF

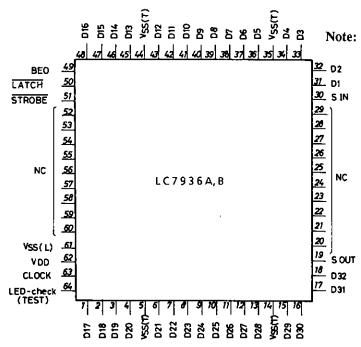
Equivalent Circuit Block Diagram



Output Driver Section Equivalent Circuit



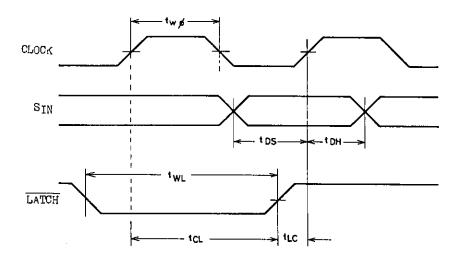
Pin Assignment



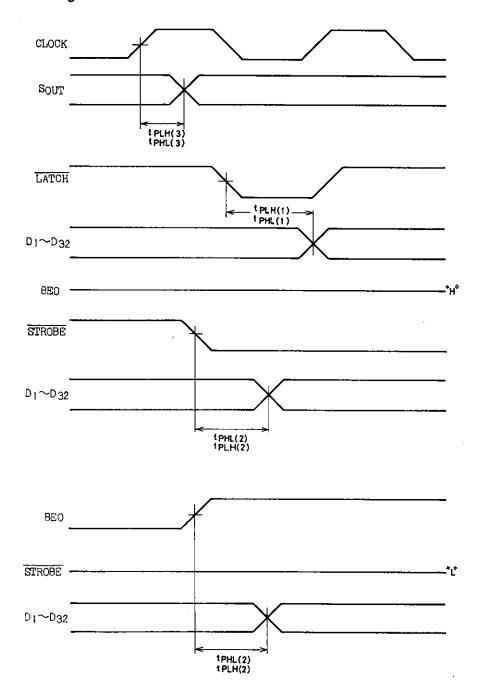
Note: Pins 24, 25 of NC pins are connected to the substrate (=V_{DD}) and must be kept open. Other NC pins must be also kept open.

2 s in When the LED-check (TEST) pin is not in use, it must not be kept open, but must be connected to GND.

Input Data Timing Chart



Output Data Timing Chart



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